

N-Channel Enhancement Mode Field Effect Transistor

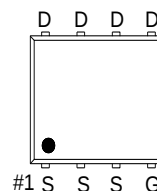
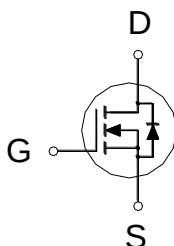
PE616BA

PDFN 3x3P

Halogen-Free & Lead-Free

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
30V	7m Ω	36A



G. GATE
D. DRAIN
S. SOURCE



ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^{\circ}\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	30	V
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25\text{ }^{\circ}\text{C}$	I_D	36	A
	$T_C = 100\text{ }^{\circ}\text{C}$		23	
Pulsed Drain Current ¹		I_{DM}	100	
Continuous Drain Current	$T_A = 25\text{ }^{\circ}\text{C}$	I_D	12	
	$T_A = 70\text{ }^{\circ}\text{C}$		9.2	
Avalanche Current		I_{AS}	23	mJ
Avalanche Energy		E_{AS}	26.4	
Power Dissipation	$T_C = 25\text{ }^{\circ}\text{C}$	P_D	16.7	W
	$T_C = 100\text{ }^{\circ}\text{C}$		6.7	
Power Dissipation	$T_A = 25\text{ }^{\circ}\text{C}$	P_D	1.7	W
	$T_A = 70\text{ }^{\circ}\text{C}$		1	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	$^{\circ}\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		75	$^{\circ}\text{C} / \text{W}$
Junction-to-Case	$R_{\theta JC}$		7	

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^{\circ}\text{C}$.

ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^{\circ}\text{C}$, Unless Otherwise Noted)

ELECTRICAL CHARACTERISTICS (T _J = 25 °C, unless otherwise noted)						
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250μA	30			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	1.35	1.8	3	

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Gate-Body Leakage	I_{GSS}		$V_{DS} = 0V, V_{GS} = \pm 20V$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}		$V_{DS} = 24V, V_{GS} = 0V$			1	μA
			$V_{DS} = 20V, V_{GS} = 0V, T_J = 55\text{ }^{\circ}C$			10	
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$		$V_{GS} = 4.5V, I_D = 12A$		7	9.5	m Ω
			$V_{GS} = 10V, I_D = 12A$		5.4	7	
Forward Transconductance ¹	g_{fs}		$V_{DS} = 5V, I_D = 12A$		55		S
DYNAMIC							
Input Capacitance	C_{iss}		$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		835		pF
Output Capacitance	C_{oss}				158		
Reverse Transfer Capacitance	C_{rss}				96		
Gate Resistance	R_g		$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		2.4		Ω
Total Gate Charge ²	Q_g	$V_{GS} = 10V$	$V_{DS} = 15V, I_D = 12A$		17.7		nC
		$V_{GS} = 4.5V$			9.5		
Gate-Source Charge ²	Q_{gs}				2.3		
Gate-Drain Charge ²	Q_{gd}				5.1		
Turn-On Delay Time ²	$t_{d(on)}$			$V_{DS} = 15V, $ $I_D \cong 12A, V_{GS} = 10V, R_{GEN} = 6\Omega$		27	
Rise Time ²	t_r				23		
Turn-Off Delay Time ²	$t_{d(off)}$				51		
Fall Time ²	t_f				24		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25\text{ }^{\circ}C$)							
Continuous Current	I_S					14	A
Forward Voltage ¹	V_{SD}		$I_F = 12A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	t_{rr}		$I_F = 12A, di_F/dt = 100A / \mu S$		13.3		nS
Reverse Recovery Charge	Q_{rr}				5.2		nC

¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

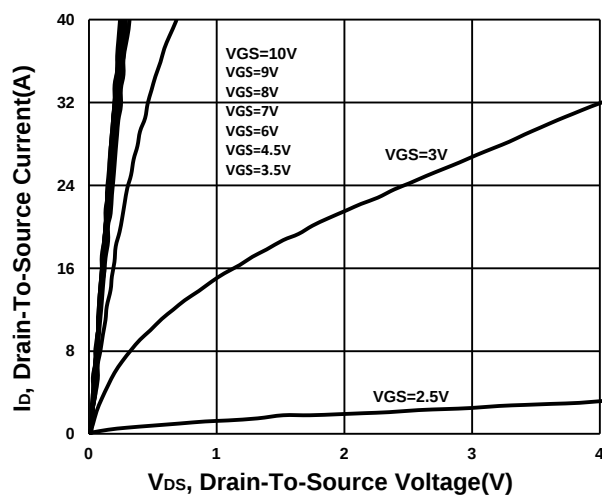
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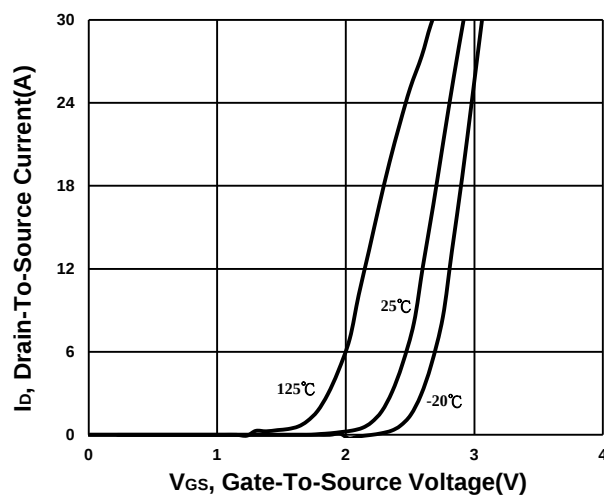
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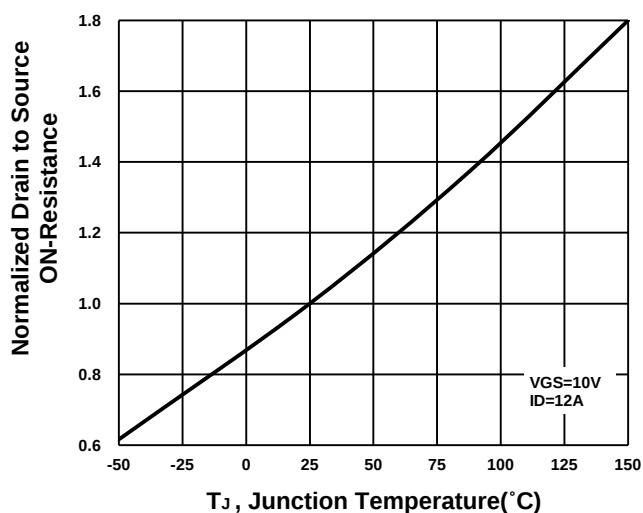
Output Characteristics



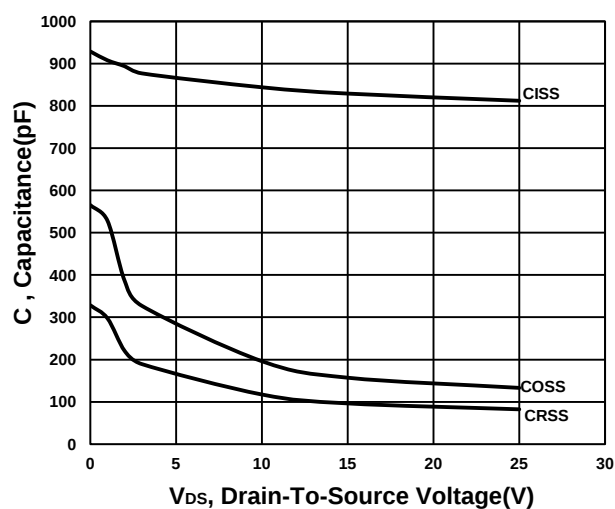
Transfer Characteristics



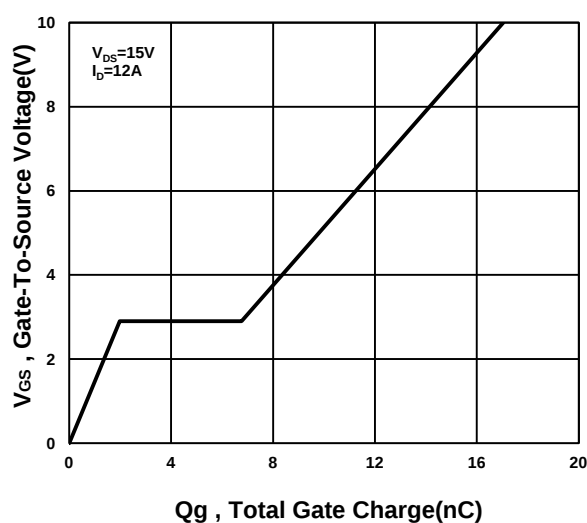
On-Resistance VS Temperature



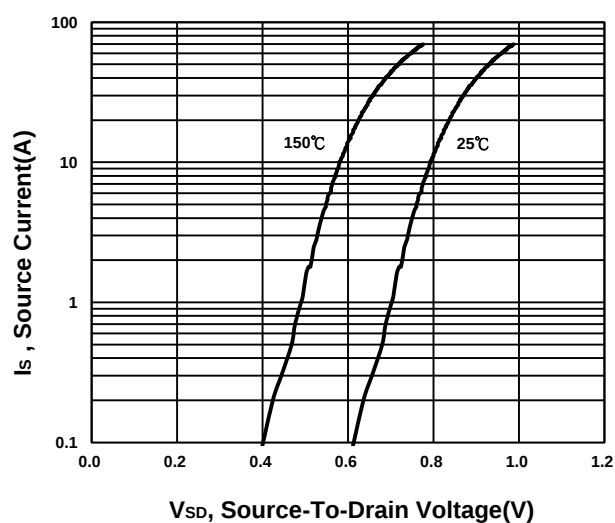
Capacitance Characteristic



Gate charge Characteristics



Source-Drain Diode Forward Voltage



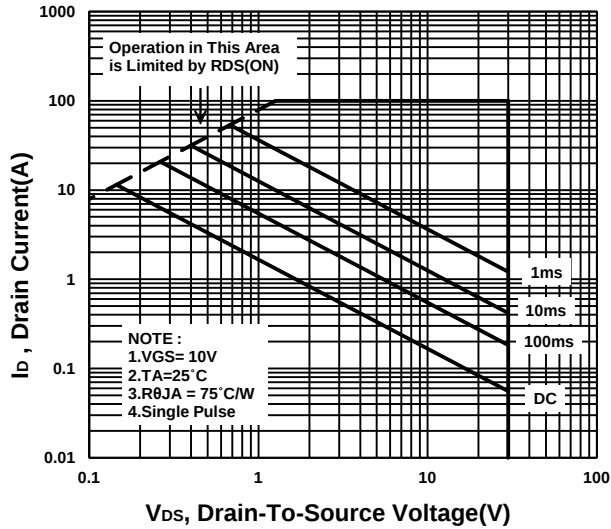
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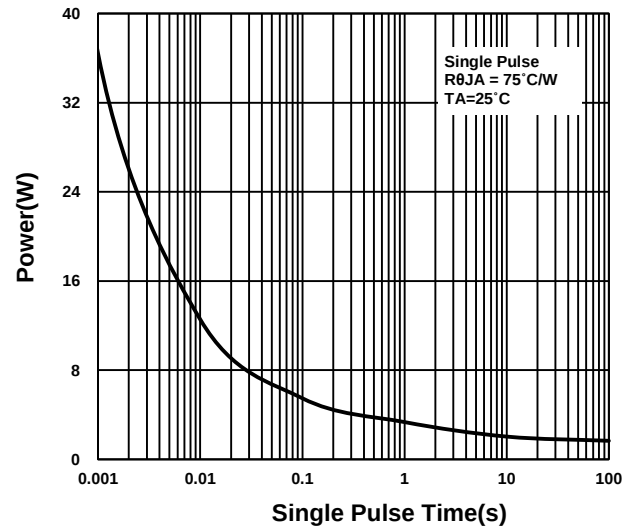
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Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

